FORM PT	ΓΟ-14	449 (Modified) U.S Dept	of Commerce	Atty Docke	et No.		Appln.	No.	
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					Matthew J	. Jolley,	et al.			
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			U.S. P.	ATENT DOCU	MENTS					
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Initials		Number	1010010			0.50	10000	4		
KF	AA	5,371,373	12/06/94	Shibata, et al.		250	492.22 11/16/9			
KK	BB	5,852,443	12/22/98	Kenworthy		345	431	06/2		
KF	CC	6,035,113	03/07/00	Gerber et al.		395	500.2	01/0	01/05/98	
rt	DD	5,533,170	07/02/96	Teitzel et al.		358	001.8	11/2	11/22/94	
KF	EE	5,239,624	08/24/93	Cook et al.		395	125	04/1	04/17/91	
			FOREIGN	PATENT DO	CUMENTS					
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Initials		Number						YES	NC	
KF	FF	WO 98/38597	09/03/98	PCT		G06K	15/12	X		
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			ОТІ	HER DOCUME	NTS					
4	GG	Johansson,	C., et al., "S	Scalable Patter	n Generato	r Data i	Path – F	or the		
K-F		Future," 8 pages (2000).								
	НН	Buck, P., et a	al., <i>"Integra</i>	ntion of the Mic	ronic Omeg	ga6500	into the i	Mask		
KF		Manufacturir	ng Environr	ment," 9 pages	(2000).					
Examiner	,			D	ate Consid	ered				
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